

**AMENDMENT AND PRESENTATION OF CLAIMS**

Please replace all prior claims in the present application with the following claims, in which no claims are canceled, withdrawn from consideration, currently amended, or newly presented.

1. (Previously Presented) A high-frequency measuring system for measuring a device under test, comprising:

a measuring-device unit; and

at least one high-frequency module, wherein each high-frequency module is placed spatially separated from the measuring-device unit and each high-frequency module is connected to the measuring-device unit via a digital interface for transmitting data to the at least one high-frequency module, wherein

processing of input data originating from the measuring-device unit to form a bitstream for transmission via the digital interface includes assigning symbols to states in a state diagram of an I-Q (in phase – quadrature phase) level in the measuring-device unit, or

a digitized intermediate-frequency signal is transmitted via the digital interface.

2. (Previously Presented) A high-frequency measuring system according to claim 1, wherein the at least one high-frequency module comprises a transmitter device or a receiver device for communication with the device under test.

3. (Previously Presented) A high-frequency measuring system according to claim 1, wherein the digital interface is a serial interface.

4. (Previously Presented) A high-frequency measuring system according to claim 1, wherein the digital interface is a parallel interface.

5. (Previously Presented) A high-frequency measuring system according to claim 1, wherein the digital interface is an optical interface.

6. (Previously Presented) A high-frequency measuring system according to claim 1, wherein the digital interface is an electrical interface.

7. (Previously Presented) A high-frequency measuring system according to claim 1, wherein the at least one high-frequency module is supplied with electrical energy via a power-supply unit independent from the measuring-device unit.

8. (Previously Presented) A high-frequency measuring system according to claim 1, wherein a plurality of identical ports are provided on the measuring-device unit for the digital interface.

9. (Previously Presented) A high-frequency measuring system according to claim 1, wherein a plurality of different ports are provided on the measuring-device unit for the digital interface.

10. (Previously Presented) A high-frequency measuring system according to claim 1, wherein control data or user data is transmitted in a standardized form via the digital interface, and wherein the at least one high-frequency module comprises means for processing a high-frequency signal with regard to the transmission of data in standardized form via the digital

interface or for processing the data transmitted in standardized form with regard to at least one predetermined transmission standard for the high-frequency signal.